



## 17. TEST PHOTOGRAPHS

See following Attached Pages for setup photographs.

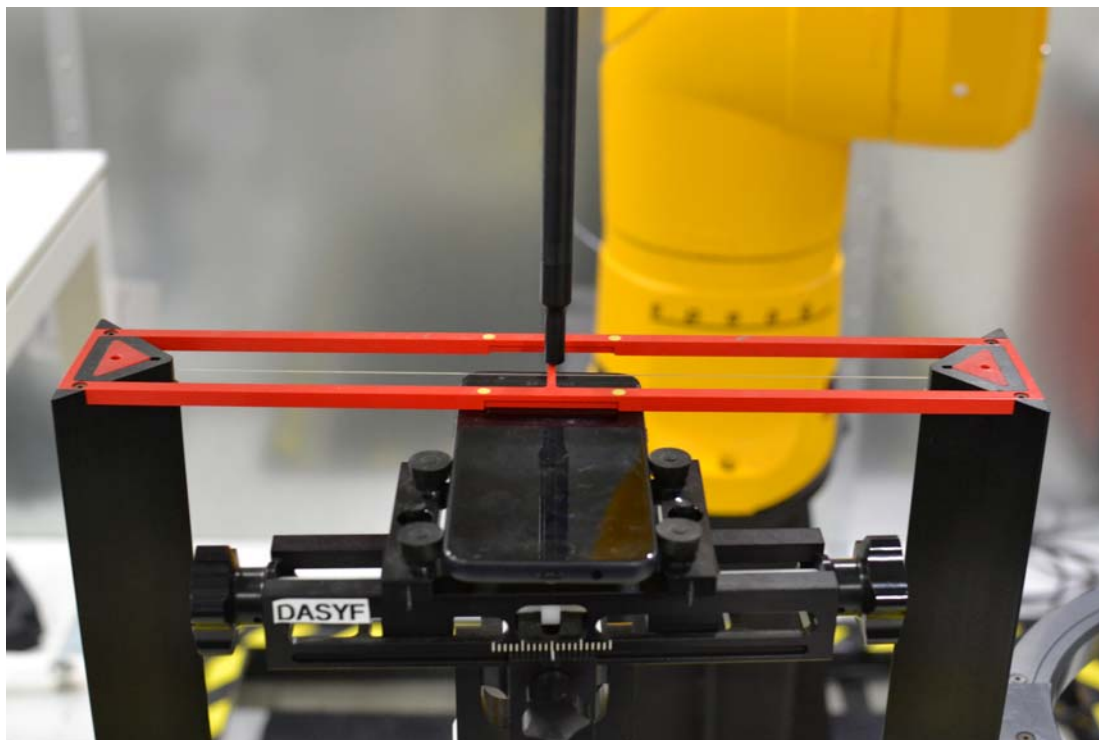
|  |   |                                       |   |  |
|--|---|---------------------------------------|---|--|
| <b>FCC ID:</b> A3LSMJ337V                  |  <b>PCTEST</b><br>ENGINEERING LABORATORY, INC. | <b>HAC (RF EMISSIONS) TEST REPORT</b> |  | <b>Approved by:</b><br>Quality Manager |
| <b>Filename:</b><br>1M1803190049-09-R1.A3L | <b>Test Dates:</b><br>04/09/2018 - 04/13/2018   | <b>DUT Type:</b><br>Portable Handset  | Page 70 of 72   |  |

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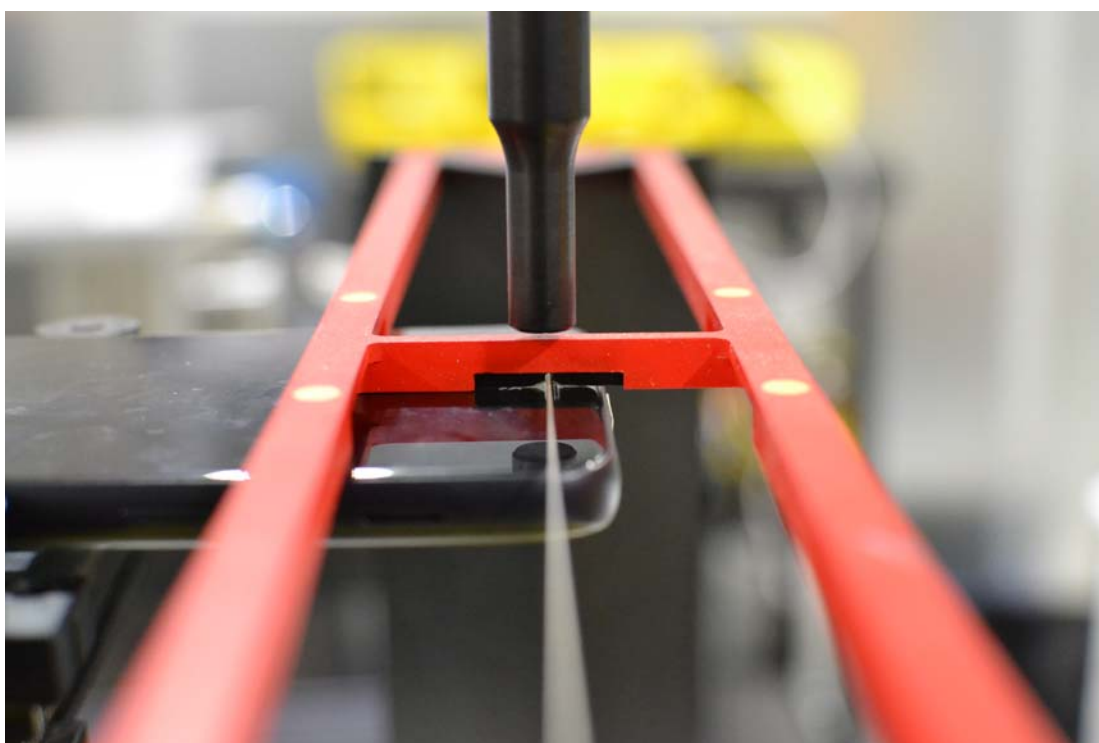
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**Figure 17-1**  
**Ear Reference Point HAC Phantom Alignment**



**Figure 17-2**  
**HAC Phantom Plane Alignment**

|                                     |   |                                |   |                                 |
|-------------------------------------|---|--------------------------------|---|---------------------------------|
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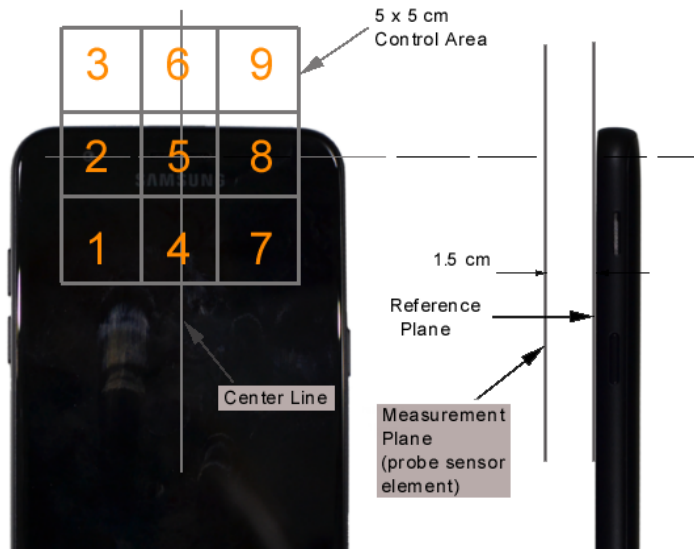




Figure 17-3 5x5 Scan grid above WD



Figure 17-4 E-Field WD Scan overlay

|                                     |  |                                |   |                                 |
|-------------------------------------|--|--------------------------------|---|---------------------------------|
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